Application/Control No. Applicant(s)/Patent Under Reexamination 09/898,710 CHIN ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1732 Mark Eashoo, Ph.D. **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 264/108 06-1997 van Muiden, Johannes Gerardus Maria US-5,639,409 Lindsay, Erin J. 264/167 В US-5,059,375 10-1991 12-1988 Kurth et al. 264/130 С US-4,790,970 US-D Ε US-F US-US-G US-Н 1 US-US-J US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Name Classification Country Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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